Search Notes (continued)	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/851,674	VAIDYANATHAN ET AL.
	Examiner	Art Unit	
	Jerry Lin	1631	

SEARCHED

Class	Subclass	Date	Examiner
702	19	4/7/2005	JL
702	20	4/7/2005	JL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Databases: West	4/7/2005	JL
Terms: database, sequence, offset, pattern, data mining, difference-in-position	4/7/2005	JL